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Sheet 1 of 2

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 125714		APPLICATION NO. New U.S. National Stage of PCT/JP2004/012114	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Susumu NODA et al.			
				FILING DATE February 2, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
JR	1	US 2002/0191905 A1	12/19/2002	PRATHER et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
JR	2	WO 98/57207	12/17/1998	WIPO			
↓	3	WO 2004/068205 A1	08/12/2004	WIPO	X		
	4	WO 01/20379 A1	03/22/2001	WIPO			
	5	JP A 62-100706	05/11/1987	JAPAN	X		
	6	JP A 2001-272555	10/05/2001	JAPAN	X	X	
	7	JP A 2001-228347	08/24/2001	JAPAN	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
JR	8	Yoshimasu SUGIMOTO et al; 29a-YN-5; "Design and characterization of coupling-controlled directional coupler (CC-DC) Based on photonic-crystal FESTA"; March 2003; p. 1137					
↓	9	Yoshihiro AKAHANE et al; "Design of a channel drop filter by using a donor-type cavity with high-quality factor in a two-dimensional photonic crystal slab"; Applied Physics Letters; Volume 82, Number 9; March 3, 2003; pp. 1341-1343					
	10	Bong-Shik SONG et al; "Photonic Devices Based on In-Plane Hetero Photonic Crystals"; Science; Vol. 300; June 6, 2003; p. 1537, right column, lines 1-9, Fig. 1D					
	11	B.S. SONG et al; 29a-YN-4; "Improvement of Optical Add/Drop Filtering efficiency by using an In-Plane Hetero structure Interface"; March 2003; p. 1137					
↓	12	AKAHANE et al; 29a-YN-9; "Drastic Increase of Quality Factor of Defect-Cavities in 2D Photonic Crystal Slabs by Modifying Defect Structure"; March 2003; p. 1138					
	13	AKAHANE et al; 1p-ZM-3; "Optical Add/Drop Devices Using 2D Photonic Crystal - Design of device structures to achieve flat-top transfer function in filtering responses"; 2003; p. 944					
EXAMINER				/Jerry Rahl1/		DATE CONSIDERED 01/07/2007	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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